Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/755,866	WEIGL ET AL.	
Examiner	Art Unit	
Soon D. Hyun	2661	

	SEARCHED					
Class	Subclass	Date	Examiner			
		-				
<u></u>						
	-					
		!				
		,				

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
interference prin		2/9/2006	НҮ

DATE	
	EXMŔ
2/8/2006	НҮ
	-
	2/8/2006